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### Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Product Status	Active
Number of LABs/CLBs	96
Number of Logic Elements/Cells	432
Total RAM Bits	16384
Number of I/O	60
Number of Gates	15000
Voltage - Supply	2.375V ~ 2.625V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	100-TQFP
Supplier Device Package	100-VQFP (14x14)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/xilinx/xc2s15-5vq100c">https://www.e-xfl.com/product-detail/xilinx/xc2s15-5vq100c</a>

## Introduction

The Spartan®-II Field-Programmable Gate Array family gives users high performance, abundant logic resources, and a rich feature set, all at an exceptionally low price. The six-member family offers densities ranging from 15,000 to 200,000 system gates, as shown in [Table 1](#). System performance is supported up to 200 MHz. Features include block RAM (to 56K bits), distributed RAM (to 75,264 bits), 16 selectable I/O standards, and four DLLs. Fast, predictable interconnect means that successive design iterations continue to meet timing requirements.

The Spartan-II family is a superior alternative to mask-programmed ASICs. The FPGA avoids the initial cost, lengthy development cycles, and inherent risk of conventional ASICs. Also, FPGA programmability permits design upgrades in the field with no hardware replacement necessary (impossible with ASICs).

## Features

- Second generation ASIC replacement technology
  - Densities as high as 5,292 logic cells with up to 200,000 system gates
  - Streamlined features based on Virtex® FPGA architecture
  - Unlimited reprogrammability
  - Very low cost
  - Cost-effective 0.18 micron process
- System level features
  - SelectRAM™ hierarchical memory:
    - 16 bits/LUT distributed RAM
    - Configurable 4K bit block RAM
    - Fast interfaces to external RAM
  - Fully PCI compliant
  - Low-power segmented routing architecture
  - Full readback ability for verification/observability
  - Dedicated carry logic for high-speed arithmetic
  - Efficient multiplier support
  - Cascade chain for wide-input functions
  - Abundant registers/latches with enable, set, reset
  - Four dedicated DLLs for advanced clock control
  - Four primary low-skew global clock distribution nets
  - IEEE 1149.1 compatible boundary scan logic
- Versatile I/O and packaging
  - Pb-free package options
  - Low-cost packages available in all densities
  - Family footprint compatibility in common packages
  - 16 high-performance interface standards
  - Hot swap Compact PCI friendly
  - Zero hold time simplifies system timing
- Core logic powered at 2.5V and I/Os powered at 1.5V, 2.5V, or 3.3V
- Fully supported by powerful Xilinx® ISE® development system
  - Fully automatic mapping, placement, and routing

**Table 1: Spartan-II FPGA Family Members**

Device	Logic Cells	System Gates (Logic and RAM)	CLB Array (R x C)	Total CLBs	Maximum Available User I/O <sup>(1)</sup>	Total Distributed RAM Bits	Total Block RAM Bits
XC2S15	432	15,000	8 x 12	96	86	6,144	16K
XC2S30	972	30,000	12 x 18	216	92	13,824	24K
XC2S50	1,728	50,000	16 x 24	384	176	24,576	32K
XC2S100	2,700	100,000	20 x 30	600	176	38,400	40K
XC2S150	3,888	150,000	24 x 36	864	260	55,296	48K
XC2S200	5,292	200,000	28 x 42	1,176	284	75,264	56K

### Notes:

1. All user I/O counts do not include the four global clock/user input pins. See details in [Table 2, page 4](#).

## Revision History

Date	Version No.	Description
09/18/00	2.0	Sectioned the Spartan-II Family data sheet into four modules. Added industrial temperature range information.
10/31/00	2.1	Removed Power down feature.
03/05/01	2.2	Added statement on PROMs.
11/01/01	2.3	Updated Product Availability chart. Minor text edits.
09/03/03	2.4	Added device part marking.
08/02/04	2.5	Added information on Pb-free packaging options and removed discontinued options.
06/13/08	2.8	Updated description and links. Updated all modules for continuous page, figure, and table numbering. Synchronized all modules to v2.8.

By default, these operations are synchronized to CCLK. The entire start-up sequence lasts eight cycles, called C0-C7, after which the loaded design is fully functional. The default timing for start-up is shown in the top half of Figure 13. The four operations can be selected to switch on any CCLK cycle C1-C6 through settings in the Xilinx software. Heavy lines show default settings.

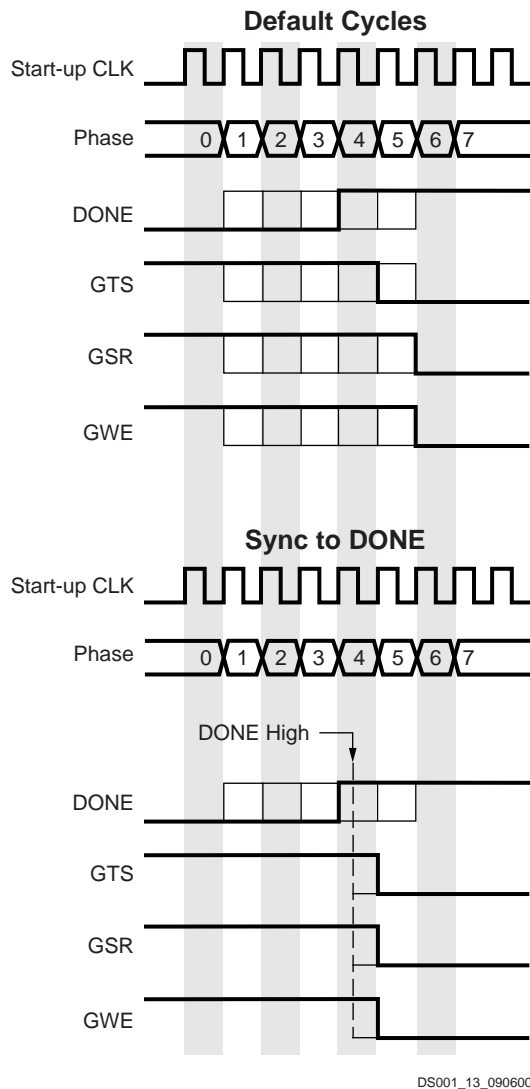


Figure 13: Start-Up Waveforms

The bottom half of Figure 13 shows another commonly used version of the start-up timing known as Sync-to-DONE. This version makes the GTS, GSR, and GWE events conditional upon the DONE pin going High. This timing is important for a daisy chain of multiple FPGAs in serial mode, since it ensures that all FPGAs go through start-up together, after all their DONE pins have gone High.

Sync-to-DONE timing is selected by setting the GTS, GSR, and GWE cycles to a value of DONE in the configuration options. This causes these signals to transition one clock cycle after DONE externally transitions High.

## Serial Modes

There are two serial configuration modes: In Master Serial mode, the FPGA controls the configuration process by driving CCLK as an output. In Slave Serial mode, the FPGA passively receives CCLK as an input from an external agent (e.g., a microprocessor, CPLD, or second FPGA in master mode) that is controlling the configuration process. In both modes, the FPGA is configured by loading one bit per CCLK cycle. The MSB of each configuration data byte is always written to the DIN pin first.

See Figure 14 for the sequence for loading data into the Spartan-II FPGA serially. This is an expansion of the "Load Configuration Data Frames" block in Figure 11. Note that  $\overline{CS}$  and  $\overline{WRITE}$  normally are not used during serial configuration. To ensure successful loading of the FPGA, do not toggle  $\overline{WRITE}$  with  $\overline{CS}$  Low during serial configuration.

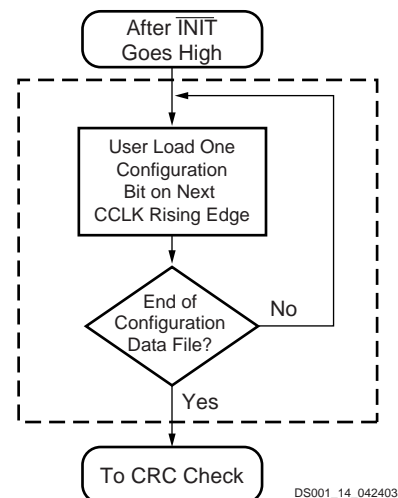


Figure 14: Loading Serial Mode Configuration Data

## Design Considerations

This section contains more detailed design information on the following features:

- Delay-Locked Loop . . . see [page 27](#)
- Block RAM . . . see [page 32](#)
- Versatile I/O . . . see [page 36](#)

## Using Delay-Locked Loops

The Spartan-II FPGA family provides up to four fully digital dedicated on-chip Delay-Locked Loop (DLL) circuits which provide zero propagation delay, low clock skew between output clock signals distributed throughout the device, and advanced clock domain control. These dedicated DLLs can be used to implement several circuits that improve and simplify system level design.

## Introduction

Quality on-chip clock distribution is important. Clock skew and clock delay impact device performance and the task of managing clock skew and clock delay with conventional clock trees becomes more difficult in large devices. The Spartan-II family of devices resolve this potential problem by providing up to four fully digital dedicated on-chip Delay-Locked Loop (DLL) circuits which provide zero propagation delay and low clock skew between output clock signals distributed throughout the device.

Each DLL can drive up to two global clock routing networks within the device. The global clock distribution network minimizes clock skews due to loading differences. By monitoring a sample of the DLL output clock, the DLL can compensate for the delay on the routing network, effectively eliminating the delay from the external input port to the individual clock loads within the device.

In addition to providing zero delay with respect to a user source clock, the DLL can provide multiple phases of the source clock. The DLL can also act as a clock doubler or it can divide the user source clock by up to 16.

Clock multiplication gives the designer a number of design alternatives. For instance, a 50 MHz source clock doubled by the DLL can drive an FPGA design operating at 100 MHz. This technique can simplify board design because the clock path on the board no longer distributes such a high-speed signal. A multiplied clock also provides designers the option of time-domain-multiplexing, using one circuit twice per clock cycle, consuming less area than two copies of the same circuit.

The DLL can also act as a clock mirror. By driving the DLL output off-chip and then back in again, the DLL can be used to de-skew a board level clock between multiple devices.

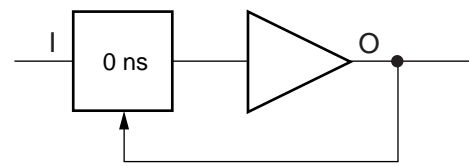
In order to guarantee the system clock establishes prior to the device "waking up," the DLL can delay the completion of

the device configuration process until after the DLL achieves lock.

By taking advantage of the DLL to remove on-chip clock delay, the designer can greatly simplify and improve system level design involving high-fanout, high-performance clocks.

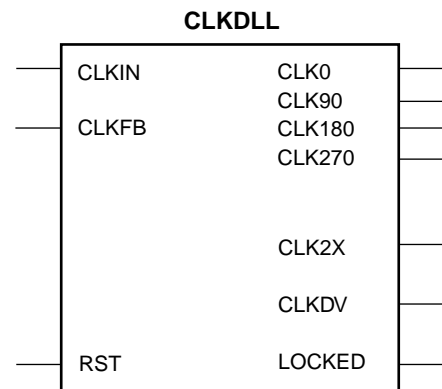
## Library DLL Primitives

Figure 22 shows the simplified Xilinx library DLL macro, BUFGDLL. This macro delivers a quick and efficient way to provide a system clock with zero propagation delay throughout the device. Figure 23 and Figure 24 show the two library DLL primitives. These primitives provide access to the complete set of DLL features when implementing more complex applications.



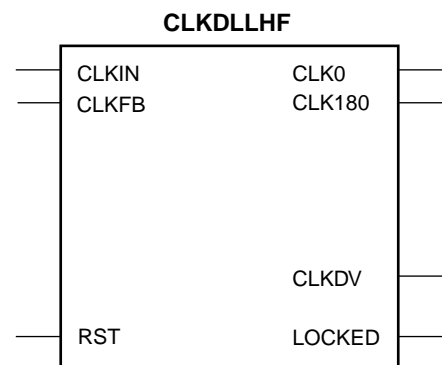
DS001\_22\_032300

Figure 22: Simplified DLL Macro BUFGDLL



DS001\_23\_032300

Figure 23: Standard DLL Primitive CLKDLL



DS001\_24\_032300

Figure 24: High-Frequency DLL Primitive CLKDLLHF

## BUFGDLL Pin Descriptions

Use the BUFGDLL macro as the simplest way to provide zero propagation delay for a high-fanout on-chip clock from an external input. This macro uses the IBUFG, CLKDLL and BUFG primitives to implement the most basic DLL application as shown in Figure 25.

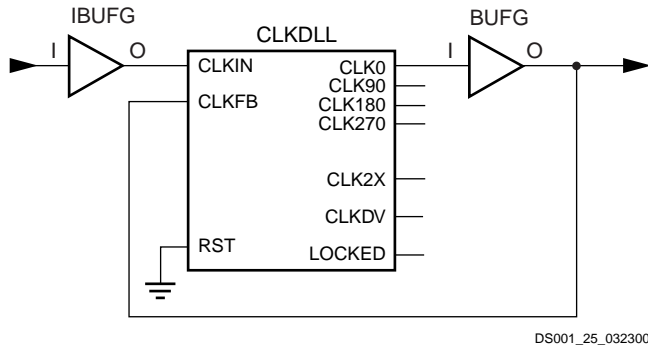


Figure 25: BUFGDLL Block Diagram

This macro does not provide access to the advanced clock domain controls or to the clock multiplication or clock division features of the DLL. This macro also does not provide access to the RST or LOCKED pins of the DLL. For access to these features, a designer must use the DLL primitives described in the following sections.

### Source Clock Input — I

The I pin provides the user source clock, the clock signal on which the DLL operates, to the BUFGDLL. For the BUFGDLL macro the source clock frequency must fall in the low frequency range as specified in the data sheet. The BUFGDLL requires an external signal source clock. Therefore, only an external input port can source the signal that drives the BUFGDLL I pin.

### Clock Output — O

The clock output pin O represents a delay-compensated version of the source clock (I) signal. This signal, sourced by a global clock buffer BUFG primitive, takes advantage of the dedicated global clock routing resources of the device.

The output clock has a 50/50 duty cycle unless you deactivate the duty cycle correction property.

## CLKDLL Primitive Pin Descriptions

The library CLKDLL primitives provide access to the complete set of DLL features needed when implementing more complex applications with the DLL.

### Source Clock Input — CLKIN

The CLKIN pin provides the user source clock (the clock signal on which the DLL operates) to the DLL. The CLKIN frequency must fall in the ranges specified in the data sheet. A global clock buffer (BUFG) driven from another CLKDLL

or one of the global clock input buffers (IBUFG) on the same edge of the device (top or bottom) must source this clock signal.

### Feedback Clock Input — CLKFB

The DLL requires a reference or feedback signal to provide the delay-compensated output. Connect only the CLK0 or CLK2X DLL outputs to the feedback clock input (CLKFB) pin to provide the necessary feedback to the DLL. Either a global clock buffer (BUFG) or one of the global clock input buffers (IBUFG) on the same edge of the device (top or bottom) must source this clock signal.

If an IBUFG sources the CLKFB pin, the following special rules apply.

1. An external input port must source the signal that drives the IBUFG I pin.
2. The CLK2X output must feed back to the device if both the CLK0 and CLK2X outputs are driving off chip devices.
3. That signal must directly drive only OBUFs and nothing else.

These rules enable the software to determine which DLL clock output sources the CLKFB pin.

### Reset Input — RST

When the reset pin RST activates, the LOCKED signal deactivates within four source clock cycles. The RST pin, active High, must either connect to a dynamic signal or be tied to ground. As the DLL delay taps reset to zero, glitches can occur on the DLL clock output pins. Activation of the RST pin can also severely affect the duty cycle of the clock output pins. Furthermore, the DLL output clocks no longer deskew with respect to one another. The DLL must be reset when the input clock frequency changes, if the device is reconfigured in Boundary-Scan mode, if the device undergoes a hot swap, and after the device is configured if the input clock is not stable during the startup sequence.

### 2x Clock Output — CLK2X

The output pin CLK2X provides a frequency-doubled clock with an automatic 50/50 duty-cycle correction. Until the CLKDLL has achieved lock, the CLK2X output appears as a 1x version of the input clock with a 25/75 duty cycle. This behavior allows the DLL to lock on the correct edge with respect to source clock. This pin is not available on the CLKDLLHF primitive.

### Clock Divide Output — CLKDV

The clock divide output pin CLKDV provides a lower frequency version of the source clock. The CLKDV\_DIVIDE property controls CLKDV such that the source clock is divided by N where N is either 1.5, 2, 2.5, 3, 4, 5, 8, or 16.

This feature provides automatic duty cycle correction. The CLKDV output pin has a 50/50 duty cycle for all values of the



support of a wide variety of applications, from general purpose standard applications to high-speed low-voltage memory busses.

Versatile I/O blocks also provide selectable output drive strengths and programmable slew rates for the LVTTTL output buffers, as well as an optional, programmable weak pull-up, weak pull-down, or weak "keeper" circuit ideal for use in external bussing applications.

Each Input/Output Block (IOB) includes three registers, one each for the input, output, and 3-state signals within the IOB. These registers are optionally configurable as either a D-type flip-flop or as a level sensitive latch.

The input buffer has an optional delay element used to guarantee a zero hold time requirement for input signals registered within the IOB.

The Versatile I/O features also provide dedicated resources for input reference voltage ( $V_{REF}$ ) and output source voltage ( $V_{CCO}$ ), along with a convenient banking system that simplifies board design.

By taking advantage of the built-in features and wide variety of I/O standards supported by the Versatile I/O features, system-level design and board design can be greatly simplified and improved.

## Fundamentals

Modern bus applications, pioneered by the largest and most influential companies in the digital electronics industry, are commonly introduced with a new I/O standard tailored specifically to the needs of that application. The bus I/O standards provide specifications to other vendors who create products designed to interface with these applications. Each standard often has its own specifications for current, voltage, I/O buffering, and termination techniques.

The ability to provide the flexibility and time-to-market advantages of programmable logic is increasingly dependent on the capability of the programmable logic device to support an ever increasing variety of I/O standards

The Versatile I/O resources feature highly configurable input and output buffers which provide support for a wide variety of I/O standards. As shown in Table 15, each buffer type can support a variety of voltage requirements.

**Table 15: Versatile I/O Supported Standards (Typical Values)**

I/O Standard	Input Reference Voltage ( $V_{REF}$ )	Output Source Voltage ( $V_{CCO}$ )	Board Termination Voltage ( $V_{TT}$ )
LVTTTL (2-24 mA)	N/A	3.3	N/A
LVC MOS2	N/A	2.5	N/A
PCI (3V/5V, 33 MHz/66 MHz)	N/A	3.3	N/A
GTL	0.8	N/A	1.2
GTL+	1.0	N/A	1.5
HSTL Class I	0.75	1.5	0.75
HSTL Class III	0.9	1.5	1.5
HSTL Class IV	0.9	1.5	1.5
SSTL3 Class I and II	1.5	3.3	1.5
SSTL2 Class I and II	1.25	2.5	1.25
CTT	1.5	3.3	1.5
AGP-2X	1.32	3.3	N/A

## Overview of Supported I/O Standards

This section provides a brief overview of the I/O standards supported by all Spartan-II devices.

While most I/O standards specify a range of allowed voltages, this document records typical voltage values only. Detailed information on each specification may be found on the Electronic Industry Alliance JEDEC website at <http://www.jedec.org>. For more details on the I/O standards and termination application examples, see XAPP179, "Using SelectIO Interfaces in Spartan-II and Spartan-IIe FPGAs."

### LVTTTL — Low-Voltage TTL

The Low-Voltage TTL (LVTTTL) standard is a general purpose EIA/JESDSA standard for 3.3V applications that uses an LVTTTL input buffer and a Push-Pull output buffer. This standard requires a 3.3V output source voltage ( $V_{CCO}$ ), but does not require the use of a reference voltage ( $V_{REF}$ ) or a termination voltage ( $V_{TT}$ ).

### LVC MOS2 — Low-Voltage CMOS for 2.5V

The Low-Voltage CMOS for 2.5V or lower (LVC MOS2) standard is an extension of the LVC MOS standard (JESD 8.5) used for general purpose 2.5V applications. This standard requires a 2.5V output source voltage ( $V_{CCO}$ ), but does not require the use of a reference voltage ( $V_{REF}$ ) or a board termination voltage ( $V_{TT}$ ).

LVTTL output buffers have selectable drive strengths.

The format for LVTTL OBUF primitive names is as follows.

OBUF\_<slew\_rate>\_<drive\_strength>

<slew\_rate> is either F (Fast), or S (Slow) and <drive\_strength> is specified in milliamps (2, 4, 6, 8, 12, 16, or 24). The default is slew rate limited with 12 mA drive.

OBUF placement restrictions require that within a given  $V_{CCO}$  bank each OBUF share the same output source drive voltage. Input buffers of any type and output buffers that do not require  $V_{CCO}$  can be placed within any  $V_{CCO}$  bank.

Table 17 summarizes the output compatibility requirements. The LOC property can specify a location for the OBUF.

Table 17: Output Standards Compatibility Requirements

Rule 1	Only outputs with standards which share compatible $V_{CCO}$ may be used within the same bank.
Rule 2	There are no placement restrictions for outputs with standards that do not require a $V_{CCO}$ .
$V_{CCO}$	Compatible Standards
3.3	LVTTL, SSTL3_I, SSTL3_II, CTT, AGP, GTL, GTL+, PCI33_3, PCI66_3
2.5	SSTL2_I, SSTL2_II, LVCMOS2, GTL, GTL+
1.5	HSTL_I, HSTL_III, HSTL_IV, GTL, GTL+

## OBUFT

The generic 3-state output buffer OBUFT, shown in Figure 39, typically implements 3-state outputs or bidirectional I/O.

With no extension or property specified for the generic OBUFT primitive, the assumed standard is slew rate limited LVTTL with 12 mA drive strength.

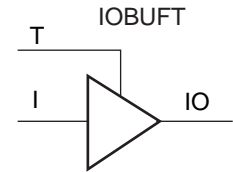
The LVTTL OBUFT can support one of two slew rate modes to minimize bus transients. By default, the slew rate for each output buffer is reduced to minimize power bus transients when switching non-critical signals.

LVTTL 3-state output buffers have selectable drive strengths.

The format for LVTTL OBUFT primitive names is as follows.

OBUFT\_<slew\_rate>\_<drive\_strength>

<slew\_rate> can be either F (Fast), or S (Slow) and <drive\_strength> is specified in milliamps (2, 4, 6, 8, 12, 16, or 24).



DS001\_39\_032300

Figure 39: 3-State Output Buffer Primitive (OBUFT)

The Versatile I/O OBUFT placement restrictions require that within a given  $V_{CCO}$  bank each OBUFT share the same output source drive voltage. Input buffers of any type and output buffers that do not require  $V_{CCO}$  can be placed within the same  $V_{CCO}$  bank.

The LOC property can specify a location for the OBUFT.

3-state output buffers and bidirectional buffers can have either a weak pull-up resistor, a weak pull-down resistor, or a weak "keeper" circuit. Control this feature by adding the appropriate primitive to the output net of the OBUFT (PULLUP, PULLDOWN, or KEEPER).

The weak "keeper" circuit requires the input buffer within the IOB to sample the I/O signal. So, OBUFTs programmed for an I/O standard that requires a  $V_{REF}$  have automatic placement of a  $V_{REF}$  in the bank with an OBUFT configured with a weak "keeper" circuit. This restriction does not affect most circuit design as applications using an OBUFT configured with a weak "keeper" typically implement a bidirectional I/O. In this case the IBUF (and the corresponding  $V_{REF}$ ) are explicitly placed.

The LOC property can specify a location for the OBUFT.

## IOBUF

Use the IOBUF primitive for bidirectional signals that require both an input buffer and a 3-state output buffer with an active high 3-state pin. The generic input/output buffer IOBUF appears in Figure 40.

With no extension or property specified for the generic IOBUF primitive, the assumed standard is LVTTL input buffer and slew rate limited LVTTL with 12 mA drive strength for the output buffer.

The LVTTL IOBUF can support one of two slew rate modes to minimize bus transients. By default, the slew rate for each output buffer is reduced to minimize power bus transients when switching non-critical signals.

LVTTL bidirectional buffers have selectable output drive strengths.

The format for LVTTL IOBUF primitive names is as follows:



ground metallization. The IC internal ground level deviates from the external system ground level for a short duration (a few nanoseconds) after multiple outputs change state simultaneously.

Ground bounce affects stable Low outputs and all inputs because they interpret the incoming signal by comparing it to the internal ground. If the ground bounce amplitude exceeds the actual instantaneous noise margin, then a non-changing input can be interpreted as a short pulse with a polarity opposite to the ground bounce.

Table 18 provides the guidelines for the maximum number of simultaneously switching outputs allowed per output power/ground pair to avoid the effects of ground bounce. Refer to Table 19 for the number of effective output power/ground pairs for each Spartan-II device and package combination.

**Table 18: Maximum Number of Simultaneously Switching Outputs per Power/Ground Pair**

Standard	Package	
	CS, FG	PQ, TQ, VQ
LVTTL Slow Slew Rate, 2 mA drive	68	36
LVTTL Slow Slew Rate, 4 mA drive	41	20
LVTTL Slow Slew Rate, 6 mA drive	29	15
LVTTL Slow Slew Rate, 8 mA drive	22	12
LVTTL Slow Slew Rate, 12 mA drive	17	9
LVTTL Slow Slew Rate, 16 mA drive	14	7
LVTTL Slow Slew Rate, 24 mA drive	9	5
LVTTL Fast Slew Rate, 2 mA drive	40	21
LVTTL Fast Slew Rate, 4 mA drive	24	12
LVTTL Fast Slew Rate, 6 mA drive	17	9
LVTTL Fast Slew Rate, 8 mA drive	13	7
LVTTL Fast Slew Rate, 12 mA drive	10	5
LVTTL Fast Slew Rate, 16 mA drive	8	4
LVTTL Fast Slew Rate, 24 mA drive	5	3
LVC MOS2	10	5
PCI	8	4
GTL	4	4
GTL+	4	4
HSTL Class I	18	9
HSTL Class III	9	5
HSTL Class IV	5	3
SSTL2 Class I	15	8

**Table 18: Maximum Number of Simultaneously Switching Outputs per Power/Ground Pair**

Standard	Package	
	CS, FG	PQ, TQ, VQ
SSTL2 Class II	10	5
SSTL3 Class I	11	6
SSTL3 Class II	7	4
CTT	14	7
AGP	9	5

**Notes:**

1. This analysis assumes a 35 pF load for each output.

**Table 19: Effective Output Power/Ground Pairs for Spartan-II Devices**

Pkg.	Spartan-II Devices					
	XC2S 15	XC2S 30	XC2S 50	XC2S 100	XC2S 150	XC2S 200
VQ100	8	8	-	-	-	-
CS144	12	12	-	-	-	-
TQ144	12	12	12	12	-	-
PQ208	-	16	16	16	16	16
FG256	-	-	16	16	16	16
FG456	-	-	-	48	48	48

## Termination Examples

Creating a design with the Versatile I/O features requires the instantiation of the desired library primitive within the design code. At the board level, designers need to know the termination techniques required for each I/O standard.

This section describes some common application examples illustrating the termination techniques recommended by each of the standards supported by the Versatile I/O features. For a full range of accepted values for the DC voltage specifications for each standard, refer to the table associated with each figure.

The resistors used in each termination technique example and the transmission lines depicted represent board level components and are not meant to represent components on the device.

## Revision History

Date	Version	Description
09/18/00	2.0	Sectioned the Spartan-II Family data sheet into four modules. Corrected banking description.
03/05/01	2.1	Clarified guidelines for applying power to $V_{CCINT}$ and $V_{CCO}$
09/03/03	2.2	<p>The following changes were made:</p> <ul style="list-style-type: none"> <li>"Serial Modes," page 20 cautions about toggling <math>\overline{WRITE}</math> during serial configuration.</li> <li>Maximum <math>V_{IH}</math> values in Table 32 and Table 33 changed to 5.5V.</li> <li>In "Boundary Scan," page 13, removed sentence about lack of INTEST support.</li> <li>In Table 9, page 17, added note about the state of I/Os after power-on.</li> <li>In "Slave Parallel Mode," page 23, explained configuration bit alignment to SelectMap port.</li> </ul>
06/13/08	2.8	Added note that TDI, TMS, and TCK have a default pull-up resistor. Added note on maximum daisy chain limit. Updated Figure 15 and Figure 18 since Mode pins can be pulled up to either 2.5V or 3.3V. Updated DLL section. Recommended using property or attribute instead of primitive to define I/O properties. Updated description and links. Updated all modules for continuous page, figure, and table numbering. Synchronized all modules to v2.8.

Input/Output Standard	$V_{IL}$		$V_{IH}$		$V_{OL}$	$V_{OH}$	$I_{OL}$	$I_{OH}$
	V, Min	V, Max	V, Min	V, Max	V, Max	V, Min	mA	mA
CTT	-0.5	$V_{REF} - 0.2$	$V_{REF} + 0.2$	3.6	$V_{REF} - 0.4$	$V_{REF} + 0.4$	8	-8
AGP	-0.5	$V_{REF} - 0.2$	$V_{REF} + 0.2$	3.6	10% $V_{CCO}$	90% $V_{CCO}$	Note (2)	Note (2)

**Notes:**

1.  $V_{OL}$  and  $V_{OH}$  for lower drive currents are sample tested.
2. Tested according to the relevant specifications.

## Switching Characteristics

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE

in the Xilinx Development System) and back-annotated to the simulation netlist. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Spartan-II devices unless otherwise noted.

### Global Clock Input to Output Delay for LVTTL, with DLL (Pin-to-Pin)<sup>(1)</sup>

Symbol	Description	Device	Speed Grade			Units
			All	-6	-5	
			Min	Max	Max	
$T_{ICKOFDLL}$	Global clock input to output delay using output flip-flop for LVTTL, 12 mA, fast slew rate, <i>with</i> DLL.	All		2.9	3.3	ns

**Notes:**

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at 1.4V with 35 pF external capacitive load for LVTTL. The 35 pF load does not apply to the Min values. For other I/O standards and different loads, see the tables ["Constants for Calculating TIOOP"](#) and ["Delay Measurement Methodology,"](#) page 60.
3. DLL output jitter is already included in the timing calculation.
4. For data *output* with different standards, adjust delays with the values shown in ["IOB Output Delay Adjustments for Different Standards,"](#) page 59. For a global clock input with standards other than LVTTL, adjust delays with values from the ["I/O Standard Global Clock Input Adjustments,"](#) page 61.

### Global Clock Input to Output Delay for LVTTL, without DLL (Pin-to-Pin)<sup>(1)</sup>

Symbol	Description	Device	Speed Grade			Units
			All	-6	-5	
			Min	Max	Max	
$T_{ICKOF}$	Global clock input to output delay using output flip-flop for LVTTL, 12 mA, fast slew rate, <i>without</i> DLL.	XC2S15		4.5	5.4	ns
		XC2S30		4.5	5.4	ns
		XC2S50		4.5	5.4	ns
		XC2S100		4.6	5.5	ns
		XC2S150		4.6	5.5	ns
		XC2S200		4.7	5.6	ns

**Notes:**

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at 1.4V with 35 pF external capacitive load for LVTTL. The 35 pF load does not apply to the Min values. For other I/O standards and different loads, see the tables ["Constants for Calculating TIOOP"](#) and ["Delay Measurement Methodology,"](#) page 60.
3. For data *output* with different standards, adjust delays with the values shown in ["IOB Output Delay Adjustments for Different Standards,"](#) page 59. For a global clock input with standards other than LVTTL, adjust delays with values from the ["I/O Standard Global Clock Input Adjustments,"](#) page 61.

## IOB Input Delay Adjustments for Different Standards<sup>(1)</sup>

Input delays associated with the pad are specified for LVTTTL. For other standards, adjust the delays by the values shown. A delay adjusted in this way constitutes a worst-case limit.

Symbol	Description	Standard	Speed Grade		Units
			-6	-5	
Data Input Delay Adjustments					
T <sub>ILVTTL</sub>	Standard-specific data input delay adjustments	LVTTTL	0	0	ns
T <sub>ILVCMOS2</sub>		LVCMSO2	−0.04	−0.05	ns
T <sub>IPCI33_3</sub>		PCI, 33 MHz, 3.3V	−0.11	−0.13	ns
T <sub>IPCI33_5</sub>		PCI, 33 MHz, 5.0V	0.26	0.30	ns
T <sub>IPCI66_3</sub>		PCI, 66 MHz, 3.3V	−0.11	−0.13	ns
T <sub>IGTL</sub>		GTL	0.20	0.24	ns
T <sub>IGTLP</sub>		GTL+	0.11	0.13	ns
T <sub>IHSTL</sub>		HSTL	0.03	0.04	ns
T <sub>ISSTL2</sub>		SSTL2	−0.08	−0.09	ns
T <sub>ISSTL3</sub>		SSTL3	−0.04	−0.05	ns
T <sub>ICTT</sub>		CTT	0.02	0.02	ns
T <sub>IAGP</sub>		AGP	−0.06	−0.07	ns

### Notes:

1. Input timing for LVTTTL is measured at 1.4V. For other I/O standards, see the table ["Delay Measurement Methodology," page 60](#).

## DLL Timing Parameters

All devices are 100 percent functionally tested. Because of the difficulty in directly measuring many internal timing parameters, those parameters are derived from benchmark

timing patterns. The following guidelines reflect worst-case values across the recommended operating conditions.

Symbol	Description	Speed Grade				Units
		-6		-5		
		Min	Max	Min	Max	
F <sub>CLKINH</sub>	Input clock frequency (CLKDLLHF)	60	200	60	180	MHz
F <sub>CLKINL</sub>	Input clock frequency (CLKDLL)	25	100	25	90	MHz
T <sub>DLLPWH</sub>	Input clock pulse width (CLKDLLHF)	2.0	-	2.4	-	ns
T <sub>DLLPWL</sub>	Input clock pulse width (CLKDLL)	2.5	-	3.0	-	ns

## DLL Clock Tolerance, Jitter, and Phase Information

All DLL output jitter and phase specifications were determined through statistical measurement at the package pins using a clock mirror configuration and matched drivers.

Figure 52, page 63, provides definitions for various parameters in the table below.

Symbol	Description	$F_{CLKIN}$	CLKDLLHF		CLKDLL		Units
			Min	Max	Min	Max	
$T_{IPTOL}$	Input clock period tolerance		-	1.0	-	1.0	ns
$T_{IJITCC}$	Input clock jitter tolerance (cycle-to-cycle)		-	±150	-	±300	ps
$T_{LOCK}$	Time required for DLL to acquire lock	> 60 MHz	-	20	-	20	μs
		50-60 MHz	-	-	-	25	μs
		40-50 MHz	-	-	-	50	μs
		30-40 MHz	-	-	-	90	μs
		25-30 MHz	-	-	-	120	μs
$T_{OJITCC}$	Output jitter (cycle-to-cycle) for any DLL clock output <sup>(1)</sup>		-	±60	-	±60	ps
$T_{PHIO}$	Phase offset between CLKIN and CLKO <sup>(2)</sup>		-	±100	-	±100	ps
$T_{PHOO}$	Phase offset between clock outputs on the DLL <sup>(3)</sup>		-	±140	-	±140	ps
$T_{PHIOM}$	Maximum phase difference between CLKIN and CLKO <sup>(4)</sup>		-	±160	-	±160	ps
$T_{PHOOM}$	Maximum phase difference between clock outputs on the DLL <sup>(5)</sup>		-	±200	-	±200	ps

### Notes:

- Output Jitter** is cycle-to-cycle jitter measured on the DLL output clock, *excluding* input clock jitter.
- Phase Offset between CLKIN and CLKO** is the worst-case fixed time difference between rising edges of CLKIN and CLKO, *excluding* output jitter and input clock jitter.
- Phase Offset between Clock Outputs on the DLL** is the worst-case fixed time difference between rising edges of any two DLL outputs, *excluding* Output Jitter and input clock jitter.
- Maximum Phase Difference between CLKIN and CLKO** is the sum of Output Jitter and Phase Offset between CLKIN and CLKO, or the greatest difference between CLKIN and CLKO rising edges due to DLL alone (*excluding* input clock jitter).
- Maximum Phase Difference between Clock Outputs on the DLL** is the sum of Output Jitter and Phase Offset between any DLL clock outputs, or the greatest difference between any two DLL output rising edges due to DLL alone (*excluding* input clock jitter).

Table 36: Spartan-II Family Package Options

Package	Leads	Type	Maximum I/O	Lead Pitch (mm)	Footprint Area (mm)	Height (mm)	Mass <sup>(1)</sup> (g)
VQ100 / VQG100	100	Very Thin Quad Flat Pack (VQFP)	60	0.5	16 x 16	1.20	0.6
TQ144 / TQG144	144	Thin Quad Flat Pack (TQFP)	92	0.5	22 x 22	1.60	1.4
CS144 / CSG144	144	Chip Scale Ball Grid Array (CSBGA)	92	0.8	12 x 12	1.20	0.3
PQ208 / PQG208	208	Plastic Quad Flat Pack (PQFP)	140	0.5	30.6 x 30.6	3.70	5.3
FG256 / FGG256	256	Fine-pitch Ball Grid Array (FBGA)	176	1.0	17 x 17	2.00	0.9
FG456 / FGG456	456	Fine-pitch Ball Grid Array (FBGA)	284	1.0	23 x 23	2.60	2.2

**Notes:**

- Package mass is  $\pm 10\%$ .

Note: Some early versions of Spartan-II devices, including the XC2S15 and XC2S30 ES devices and the XC2S150 with date code 0045 or earlier, included a power-down pin. For more information, see [Answer Record 10500](#).

## VCCO Banks

Some of the I/O standards require specific  $V_{CCO}$  voltages. These voltages are externally connected to device pins that serve groups of IOBs, called banks. Eight I/O banks result from separating each edge of the FPGA into two banks (see [Figure 3](#) in Module 2). Each bank has multiple  $V_{CCO}$  pins which must be connected to the same voltage. In the smaller packages, the  $V_{CCO}$  pins are connected between banks, effectively reducing the number of independent banks available (see [Table 37](#)). These interconnected banks are shown in the Pinout Tables with  $V_{CCO}$  pads for multiple banks connected to the same pin.

Table 37: Independent VCCO Banks Available

Package	VQ100 PQ208	CS144 TQ144	FG256 FG456
Independent Banks	1	4	8

## Package Overview

[Table 36](#) shows the six low-cost, space-saving production package styles for the Spartan-II family.

Each package style is available in an environmentally friendly lead-free (Pb-free) option. The Pb-free packages include an extra 'G' in the package style name. For example, the standard "CS144" package becomes "CSG144" when ordered as the Pb-free option. Leaded (non-Pb-free) packages may be available for selected devices, with the same pin-out and without the "G" in the ordering code; contact Xilinx sales for more information. The mechanical dimensions of the standard and Pb-free packages are similar, as shown in the mechanical drawings provided in [Table 38](#).

For additional package information, see [UG112: Device Package User Guide](#).

## Mechanical Drawings

Detailed mechanical drawings for each package type are available from the Xilinx web site at the specified location in [Table 38](#).

Material Declaration Data Sheets (MDDS) are also available on the [Xilinx web site](#) for each package.

Table 38: Xilinx Package Documentation

Package	Drawing	MDDS
VQ100	<a href="#">Package Drawing</a>	<a href="#">PK173_VQ100</a>
VQG100		<a href="#">PK130_VQG100</a>
TQ144	<a href="#">Package Drawing</a>	<a href="#">PK169_TQ144</a>
TQG144		<a href="#">PK126_TQG144</a>
CS144	<a href="#">Package Drawing</a>	<a href="#">PK149_CS144</a>
CSG144		<a href="#">PK103_CSG144</a>
PQ208	<a href="#">Package Drawing</a>	<a href="#">PK166_PQ208</a>
PQG208		<a href="#">PK123_PQG208</a>
FG256	<a href="#">Package Drawing</a>	<a href="#">PK151_FG256</a>
FGG256		<a href="#">PK105_FGG256</a>
FG456	<a href="#">Package Drawing</a>	<a href="#">PK154_FG456</a>
FGG456		<a href="#">PK109_FGG456</a>



## XC2S30 Device Pinouts (Continued)

XC2S30 Pad Name		VQ100	TQ144	CS144	PQ208	Bndry Scan
Function	Bank					
I/O	4	-	-	-	P87	295
I/O	4	-	-	-	P88	298
I/O	4	-	P84	K8	P89	301
I/O	4	-	P83	N9	P90	304
V <sub>CCINT</sub>	-	P42	P82	M9	P91	-
V <sub>CCO</sub>	4	-	-	-	P92	-
GND	-	-	P81	L9	P93	-
I/O	4	P43	P80	K9	P94	307
I/O	4	P44	P79	N10	P95	310
I/O	4	-	P78	M10	P96	313
I/O, V <sub>REF</sub>	4	P45	P77	L10	P98	316
I/O	4	-	-	-	P99	319
I/O	4	-	P76	N11	P100	322
I/O	4	P46	P75	M11	P101	325
I/O	4	P47	P74	L11	P102	328
GND	-	P48	P73	N12	P103	-
DONE	3	P49	P72	M12	P104	331
V <sub>CCO</sub>	4	P50	P71	N13	P105	-
V <sub>CCO</sub>	3	P50	P70	M13	P105	-
PROGRAM	-	P51	P69	L12	P106	334
I/O (INIT)	3	P52	P68	L13	P107	335
I/O (D7)	3	P53	P67	K10	P108	338
I/O	3	-	P66	K11	P109	341
I/O	3	-	-	-	P110	344
I/O, V <sub>REF</sub>	3	P54	P65	K12	P111	347
I/O	3	-	P64	K13	P113	350
I/O	3	P55	P63	J10	P114	353
I/O (D6)	3	P56	P62	J11	P115	356
GND	-	-	P61	J12	P116	-
V <sub>CCO</sub>	3	-	-	-	P117	-
I/O (D5)	3	P57	P60	J13	P119	359
I/O	3	P58	P59	H10	P120	362
I/O	3	-	-	-	P121	365
I/O	3	-	-	-	P122	368
I/O	3	-	-	-	P123	371
GND	-	-	-	-	P124	-
I/O, V <sub>REF</sub>	3	P59	P58	H11	P125	374
I/O (D4)	3	P60	P57	H12	P126	377
I/O	3	-	P56	H13	P127	380
V <sub>CCINT</sub>	-	P61	P55	G12	P128	-
I/O, TRDY <sup>(1)</sup>	3	P62	P54	G13	P129	386

## XC2S30 Device Pinouts (Continued)

XC2S30 Pad Name		VQ100	TQ144	CS144	PQ208	Bndry Scan
Function	Bank					
V <sub>CCO</sub>	3	P63	P53	G11	P130	-
V <sub>CCO</sub>	2	P63	P53	G11	P130	-
GND	-	P64	P52	G10	P131	-
I/O, IRDY <sup>(1)</sup>	2	P65	P51	F13	P132	389
I/O	2	-	-	-	P133	392
I/O	2	-	P50	F12	P134	395
I/O (D3)	2	P66	P49	F11	P135	398
I/O, V <sub>REF</sub>	2	P67	P48	F10	P136	401
GND	-	-	-	-	P137	-
I/O	2	-	-	-	P138	404
I/O	2	-	-	-	P139	407
I/O	2	-	-	-	P140	410
I/O	2	P68	P47	E13	P141	413
I/O (D2)	2	P69	P46	E12	P142	416
V <sub>CCO</sub>	2	-	-	-	P144	-
GND	-	-	P45	E11	P145	-
I/O (D1)	2	P70	P44	E10	P146	419
I/O	2	P71	P43	D13	P147	422
I/O	2	-	P42	D12	P148	425
I/O, V <sub>REF</sub>	2	P72	P41	D11	P150	428
I/O	2	-	-	-	P151	431
I/O	2	-	P40	C13	P152	434
I/O (DIN, D0)	2	P73	P39	C12	P153	437
I/O (DOUT, BUSY)	2	P74	P38	C11	P154	440
CCLK	2	P75	P37	B13	P155	443
V <sub>CCO</sub>	2	P76	P36	B12	P156	-
V <sub>CCO</sub>	1	P76	P35	A13	P156	-
TDO	2	P77	P34	A12	P157	-
GND	-	P78	P33	B11	P158	-
TDI	-	P79	P32	A11	P159	-
I/O (CS)	1	P80	P31	D10	P160	0
I/O (WRITE)	1	P81	P30	C10	P161	3
I/O	1	-	P29	B10	P162	6
I/O	1	-	-	-	P163	9
I/O, V <sub>REF</sub>	1	P82	P28	A10	P164	12
I/O	1	-	-	-	P166	15
I/O	1	P83	P27	D9	P167	18
I/O	1	P84	P26	C9	P168	21
GND	-	-	P25	B9	P169	-
V <sub>CCO</sub>	1	-	-	-	P170	-

## XC2S30 Device Pinouts (Continued)

XC2S30 Pad Name		VQ100	TQ144	CS144	PQ208	Bndry Scan
Function	Bank					
V <sub>CCINT</sub>	-	P85	P24	A9	P171	-
I/O	1	-	P23	D8	P172	24
I/O	1	-	P22	C8	P173	27
I/O	1	-	-	-	P174	30
I/O	1	-	-	-	P175	33
I/O	1	-	-	-	P176	36
GND	-	-	-	-	P177	-
I/O, V <sub>REF</sub>	1	P86	P21	B8	P178	39
I/O	1	-	-	-	P179	42
I/O	1	-	P20	A8	P180	45
I/O	1	P87	P19	B7	P181	48
I, GCK2	1	P88	P18	A7	P182	54
GND	-	P89	P17	C7	P183	-
V <sub>CCO</sub>	1	P90	P16	D7	P184	-
V <sub>CCO</sub>	0	P90	P16	D7	P184	-
I, GCK3	0	P91	P15	A6	P185	55
V <sub>CCINT</sub>	-	P92	P14	B6	P186	-
I/O	0	-	P13	C6	P187	62
I/O	0	-	-	-	P188	65
I/O, V <sub>REF</sub>	0	P93	P12	D6	P189	68
GND	-	-	-	-	P190	-
I/O	0	-	-	-	P191	71
I/O	0	-	-	-	P192	74
I/O	0	-	-	-	P193	77
I/O	0	-	P11	A5	P194	80
I/O	0	-	P10	B5	P195	83
V <sub>CCINT</sub>	-	P94	P9	C5	P196	-
V <sub>CCO</sub>	0	-	-	-	P197	-
GND	-	-	P8	D5	P198	-
I/O	0	P95	P7	A4	P199	86
I/O	0	P96	P6	B4	P200	89
I/O	0	-	-	-	P201	92

## XC2S30 Device Pinouts (Continued)

XC2S30 Pad Name		VQ100	TQ144	CS144	PQ208	Bndry Scan
Function	Bank					
I/O, V <sub>REF</sub>	0	P97	P5	C4	P203	95
I/O	0	-	-	-	P204	98
I/O	0	-	P4	A3	P205	101
I/O	0	P98	P3	B3	P206	104
TCK	-	P99	P2	C3	P207	-
V <sub>CCO</sub>	0	P100	P1	A2	P208	-
V <sub>CCO</sub>	7	P100	P144	B2	P208	-

04/18/01

### Notes:

1. IRDY and TRDY can only be accessed when using Xilinx PCI cores.
2. See "V<sub>CCO</sub> Banks" for details on V<sub>CCO</sub> banking.

## Additional XC2S30 Package Pins

### VQ100

Not Connected Pins					
P28	P29	-	-	-	-

11/02/00

### TQ144

Not Connected Pins					
P104	P105	-	-	-	-

11/02/00

### CS144

Not Connected Pins					
M3	N3	-	-	-	-

11/02/00

### PQ208

Not Connected Pins					
P7	P13	P38	P44	P55	P56
P60	P97	P112	P118	P143	P149
P165	P202	-	-	-	-

11/02/00

### Notes:

1. For the PQ208 package, P13, P38, P118, and P143, which are Not Connected Pins on the XC2S30, are assigned to V<sub>CCINT</sub> on larger devices.

## XC2S100 Device Pinouts (Continued)

XC2S100 Pad Name		TQ144	PQ208	FG256	FG456	Bndry Scan
Function	Bank					
I/O, V <sub>REF</sub>	4	P79	P95	T11	AB16	502
I/O	4	-	-	-	AB17	505
I/O	4	P78	P96	N11	V15	508
I/O	4	-	-	R12	Y16	511
I/O	4	-	P97	P11	AB18	517
I/O, V <sub>REF</sub>	4	P77	P98	T12	AB19	520
V <sub>CCO</sub>	4	-	-	V <sub>CCO</sub> Bank 4*	V <sub>CCO</sub> Bank 4*	-
GND	-	-	-	GND*	GND*	-
I/O	4	-	P99	T13	Y17	523
I/O	4	-	-	N12	V16	526
I/O	4	-	-	-	W17	529
I/O	4	P76	P100	R13	AB20	532
I/O	4	-	-	P12	AA19	535
I/O	4	P75	P101	P13	AA20	541
I/O	4	P74	P102	T14	W18	544
GND	-	P73	P103	GND*	GND*	-
DONE	3	P72	P104	R14	Y19	547
V <sub>CCO</sub>	4	P71	P105	V <sub>CCO</sub> Bank 4*	V <sub>CCO</sub> Bank 4*	-
V <sub>CCO</sub>	3	P70	P105	V <sub>CCO</sub> Bank 3*	V <sub>CCO</sub> Bank 3*	-
PROGRAM	-	P69	P106	P15	W20	550
I/O (INIT)	3	P68	P107	N15	V19	551
I/O (D7)	3	P67	P108	N14	Y21	554
I/O	3	-	-	T15	W21	560
I/O	3	P66	P109	M13	U20	563
I/O	3	-	-	-	U19	566
I/O	3	-	-	R16	T18	569
I/O	3	-	P110	M14	W22	572
GND	-	-	-	GND*	GND*	-
V <sub>CCO</sub>	3	-	-	V <sub>CCO</sub> Bank 3*	V <sub>CCO</sub> Bank 3*	-
I/O, V <sub>REF</sub>	3	P65	P111	L14	U21	575
I/O	3	-	P112	M15	T20	578
I/O	3	-	-	L12	T21	584
I/O	3	P64	P113	P16	R18	587
I/O	3	-	-	-	U22	590
I/O, V <sub>REF</sub>	3	P63	P114	L13	R19	593
I/O (D6)	3	P62	P115	N16	T22	596
GND	-	P61	P116	GND*	GND*	-

## XC2S100 Device Pinouts (Continued)

XC2S100 Pad Name		TQ144	PQ208	FG256	FG456	Bndry Scan
Function	Bank					
V <sub>CCO</sub>	3	-	P117	V <sub>CCO</sub> Bank 3*	V <sub>CCO</sub> Bank 3*	-
V <sub>CCINT</sub>	-	-	P118	V <sub>CCINT</sub> *	V <sub>CCINT</sub> *	-
I/O (D5)	3	P60	P119	M16	R21	599
I/O	3	P59	P120	K14	P18	602
I/O	3	-	-	L16	P20	605
I/O	3	-	P121	K13	P21	608
I/O	3	-	P122	L15	N18	614
I/O	3	-	P123	K12	N20	617
GND	-	-	P124	GND*	GND*	-
I/O, V <sub>REF</sub>	3	P58	P125	K16	N21	620
I/O (D4)	3	P57	P126	J16	N22	623
I/O	3	-	-	J14	M19	626
I/O	3	P56	P127	K15	M20	629
V <sub>CCINT</sub>	-	P55	P128	E5	V <sub>CCINT</sub> *	-
I/O, TRDY <sup>(1)</sup>	3	P54	P129	J15	M22	638
V <sub>CCO</sub>	3	P53	P130	V <sub>CCO</sub> Bank 3*	V <sub>CCO</sub> Bank 3*	-
V <sub>CCO</sub>	2	P53	P130	V <sub>CCO</sub> Bank 2*	V <sub>CCO</sub> Bank 2*	-
GND	-	P52	P131	GND*	GND*	-
I/O, IRDY <sup>(1)</sup>	2	P51	P132	H16	L20	641
I/O	2	-	P133	H14	L17	644
I/O	2	P50	P134	H15	L21	650
I/O	2	-	-	J13	L22	653
I/O (D3)	2	P49	P135	G16	K20	656
I/O, V <sub>REF</sub>	2	P48	P136	H13	K21	659
GND	-	-	P137	GND*	GND*	-
I/O	2	-	P138	G14	K22	662
I/O	2	-	P139	G15	J21	665
I/O	2	-	P140	G12	J18	671
I/O	2	-	-	F16	J22	674
I/O	2	P47	P141	G13	H19	677
I/O (D2)	2	P46	P142	F15	H20	680
V <sub>CCINT</sub>	-	-	P143	V <sub>CCINT</sub> *	V <sub>CCINT</sub> *	-
V <sub>CCO</sub>	2	-	P144	V <sub>CCO</sub> Bank 2*	V <sub>CCO</sub> Bank 2*	-
GND	-	P45	P145	GND*	GND*	-
I/O (D1)	2	P44	P146	E16	H22	683
I/O, V <sub>REF</sub>	2	P43	P147	F14	H18	686
I/O	2	-	-	-	G21	689
I/O	2	P42	P148	D16	G18	692

## XC2S100 Device Pinouts (Continued)

XC2S100 Pad Name		TQ144	PQ208	FG256	FG456	Bndry Scan
Function	Bank					
I/O	2	-	-	F12	G20	695
I/O	2	-	P149	E15	F19	701
I/O, V <sub>REF</sub>	2	P41	P150	F13	F21	704
V <sub>CCO</sub>	2	-	-	V <sub>CCO</sub> Bank 2*	V <sub>CCO</sub> Bank 2*	-
GND	-	-	-	GND*	GND*	-
I/O	2	-	P151	E14	F20	707
I/O	2	-	-	C16	F18	710
I/O	2	-	-	-	E21	713
I/O	2	P40	P152	E13	D22	716
I/O	2	-	-	B16	E20	719
I/O (DIN, DO)	2	P39	P153	D14	D20	725
I/O (DOUT, BUSY)	2	P38	P154	C15	C21	728
CCLK	2	P37	P155	D15	B22	731
V <sub>CCO</sub>	2	P36	P156	V <sub>CCO</sub> Bank 2*	V <sub>CCO</sub> Bank 2*	-
V <sub>CCO</sub>	1	P35	P156	V <sub>CCO</sub> Bank 1*	V <sub>CCO</sub> Bank 1*	-
TDO	2	P34	P157	B14	A21	-
GND	-	P33	P158	GND*	GND*	-
TDI	-	P32	P159	A15	B20	-
I/O ( $\overline{\text{CS}}$ )	1	P31	P160	B13	C19	0
I/O ( $\overline{\text{WRITE}}$ )	1	P30	P161	C13	A20	3
I/O	1	-	-	C12	D17	9
I/O	1	P29	P162	A14	A19	12
I/O	1	-	-	-	B18	15
I/O	1	-	-	D12	C17	18
I/O	1	-	P163	B12	D16	21
GND	-	-	-	GND*	GND*	-
V <sub>CCO</sub>	1	-	-	V <sub>CCO</sub> Bank 1*	V <sub>CCO</sub> Bank 1*	-
I/O, V <sub>REF</sub>	1	P28	P164	C11	A18	24
I/O	1	-	P165	A13	B17	27
I/O	1	-	-	D11	D15	33
I/O	1	-	P166	A12	C16	36
I/O	1	-	-	-	D14	39
I/O, V <sub>REF</sub>	1	P27	P167	E11	E14	42
I/O	1	P26	P168	B11	A16	45
GND	-	P25	P169	GND*	GND*	-

## XC2S100 Device Pinouts (Continued)

XC2S100 Pad Name		TQ144	PQ208	FG256	FG456	Bndry Scan
Function	Bank					
V <sub>CCO</sub>	1	-	P170	V <sub>CCO</sub> Bank 1*	V <sub>CCO</sub> Bank 1*	-
V <sub>CCINT</sub>	-	P24	P171	V <sub>CCINT</sub> *	V <sub>CCINT</sub> *	-
I/O	1	P23	P172	A11	C15	48
I/O	1	P22	P173	C10	B15	51
I/O	1	-	-	-	F12	54
I/O	1	-	P174	B10	C14	57
I/O	1	-	P175	D10	D13	63
I/O	1	-	P176	A10	C13	66
GND	-	-	P177	GND*	GND*	-
I/O, V <sub>REF</sub>	1	P21	P178	B9	B13	69
I/O	1	-	P179	E10	E12	72
I/O	1	-	-	A9	B12	75
I/O	1	P20	P180	D9	D12	78
I/O	1	P19	P181	A8	D11	84
I, GCK2	1	P18	P182	C9	A11	90
GND	-	P17	P183	GND*	GND*	-
V <sub>CCO</sub>	1	P16	P184	V <sub>CCO</sub> Bank 1*	V <sub>CCO</sub> Bank 1*	-
V <sub>CCO</sub>	0	P16	P184	V <sub>CCO</sub> Bank 0*	V <sub>CCO</sub> Bank 0*	-
I, GCK3	0	P15	P185	B8	C11	91
V <sub>CCINT</sub>	-	P14	P186	V <sub>CCINT</sub> *	V <sub>CCINT</sub> *	-
I/O	0	P13	P187	A7	A10	101
I/O	0	-	-	D8	B10	104

## Additional XC2S150 Package Pins

### PQ208

Not Connected Pins					
P55	P56	-	-	-	-

11/02/00

### FG256

V <sub>CCINT</sub> Pins					
C3	C14	D4	D13	E5	E12
M5	M12	N4	N13	P3	P14
V <sub>CCO</sub> Bank 0 Pins					
E8	F8	-	-	-	-
V <sub>CCO</sub> Bank 1 Pins					
E9	F9	-	-	-	-
V <sub>CCO</sub> Bank 2 Pins					
H11	H12	-	-	-	-
V <sub>CCO</sub> Bank 3 Pins					
J11	J12	-	-	-	-
V <sub>CCO</sub> Bank 4 Pins					
L9	M9	-	-	-	-
V <sub>CCO</sub> Bank 5 Pins					
L8	M8	-	-	-	-
V <sub>CCO</sub> Bank 6 Pins					
J5	J6	-	-	-	-
V <sub>CCO</sub> Bank 7 Pins					
H5	H6	-	-	-	-
GND Pins					
A1	A16	B2	B15	F6	F7
F10	F11	G6	G7	G8	G9
G10	G11	H7	H8	H9	H10
J7	J8	J9	J10	K6	K7
K8	K9	K10	K11	L6	L7
L10	L11	R2	R15	T1	T16
Not Connected Pins					
P4	R4	-	-	-	-

11/02/00

## Additional XC2S150 Package Pins (Continued)

### FG456

V <sub>CCINT</sub> Pins					
E5	E18	F6	F17	G7	G8
G9	G14	G15	G16	H7	H16
J7	J16	P7	P16	R7	R16
T7	T8	T9	T14	T15	T16
U6	U17	V5	V18	-	-
V <sub>CCO</sub> Bank 0 Pins					
F7	F8	F9	F10	G10	G11
V <sub>CCO</sub> Bank 1 Pins					
F13	F14	F15	F16	G12	G13
V <sub>CCO</sub> Bank 2 Pins					
G17	H17	J17	K16	K17	L16
V <sub>CCO</sub> Bank 3 Pins					
M16	N16	N17	P17	R17	T17
V <sub>CCO</sub> Bank 4 Pins					
T12	T13	U13	U14	U15	U16
V <sub>CCO</sub> Bank 5 Pins					
T10	T11	U7	U8	U9	U10
V <sub>CCO</sub> Bank 6 Pins					
M7	N6	N7	P6	R6	T6
V <sub>CCO</sub> Bank 7 Pins					
G6	H6	J6	K6	K7	L7
GND Pins					
A1	A22	B2	B21	C3	C20
J9	J10	J11	J12	J13	J14
K9	K10	K11	K12	K13	K14
L9	L10	L11	L12	L13	L14
M9	M10	M11	M12	M13	M14
N9	N10	N11	N12	N13	N14
P9	P10	P11	P12	P13	P14
Y3	Y20	AA2	AA21	AB1	AB22
Not Connected Pins					
A2	A6	A12	A13	A14	B11
B16	C2	C8	C9	D1	D4
D18	D19	E13	E17	E19	F11
G2	G22	H21	J1	J4	K2
K18	K19	L2	L19	M2	M17
M21	N1	P1	P5	P22	R3
R20	R22	U3	U18	V6	W4
W13	W15	W19	Y5	Y22	AA1
AA3	AA9	AA10	AA11	AA16	AB7
AB8	AB12	AB14	AB21	-	-

11/02/00

## XC2S200 Device Pinouts (Continued)

XC2S200 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
I/O	6	-	-	T2	449
I/O	6	P43	L4	U1	452
GND	-	-	GND*	GND*	-
I/O	6	-	M2	R5	455
I/O	6	-	-	V1	458
I/O	6	-	-	T5	461
I/O	6	P44	L3	U2	464
I/O, V <sub>REF</sub>	6	P45	N1	T3	467
V <sub>CCO</sub>	6	-	V <sub>CCO</sub> Bank 6*	V <sub>CCO</sub> Bank 6*	-
GND	-	-	GND*	GND*	-
I/O	6	P46	P1	T4	470
I/O	6	-	L5	W1	473
GND	-	-	GND*	GND*	-
I/O	6	-	-	V2	476
I/O	6	-	-	U4	482
I/O, V <sub>REF</sub>	6	P47	N2	Y1	485
GND	-	-	GND*	GND*	-
I/O	6	-	M4	W2	488
I/O	6	-	-	V3	491
I/O	6	-	-	V4	494
I/O	6	P48	R1	Y2	500
I/O	6	P49	M3	W3	503
M1	-	P50	P2	U5	506
GND	-	P51	GND*	GND*	-
M0	-	P52	N3	AB2	507
V <sub>CCO</sub>	6	P53	V <sub>CCO</sub> Bank 6*	V <sub>CCO</sub> Bank 6*	-
V <sub>CCO</sub>	5	P53	V <sub>CCO</sub> Bank 5*	V <sub>CCO</sub> Bank 5*	-
M2	-	P54	R3	Y4	508
I/O	5	-	-	W5	518
I/O	5	-	-	AB3	521
I/O	5	-	N5	V7	524
GND	-	-	GND*	GND*	-
I/O, V <sub>REF</sub>	5	P57	T2	Y6	527
I/O	5	-	-	AA4	530
I/O	5	-	-	AB4	536
I/O	5	-	P5	W6	539
I/O	5	P58	T3	Y7	542
GND	-	-	GND*	GND*	-

## XC2S200 Device Pinouts (Continued)

XC2S200 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
V <sub>CCO</sub>	5	-	V <sub>CCO</sub> Bank 5*	V <sub>CCO</sub> Bank 5*	-
I/O, V <sub>REF</sub>	5	P59	T4	AA5	545
I/O	5	P60	M6	AB5	548
I/O	5	-	-	V8	551
I/O	5	-	-	AA6	554
I/O	5	-	T5	AB6	557
GND	-	-	GND*	GND*	-
I/O	5	P61	N6	AA7	560
I/O	5	-	-	W7	563
I/O, V <sub>REF</sub>	5	P62	R5	W8	569
I/O	5	P63	P6	Y8	572
GND	-	P64	GND*	GND*	-
V <sub>CCO</sub>	5	P65	V <sub>CCO</sub> Bank 5*	V <sub>CCO</sub> Bank 5*	-
V <sub>CCINT</sub>	-	P66	V <sub>CCINT</sub> *	V <sub>CCINT</sub> *	-
I/O	5	P67	R6	AA8	575
I/O	5	P68	M7	V9	578
I/O	5	-	-	AB8	581
I/O	5	-	-	W9	584
I/O	5	-	-	AB9	587
GND	-	-	GND*	GND*	-
I/O	5	P69	N7	Y9	590
I/O	5	-	-	V10	593
I/O	5	-	-	AA9	596
I/O	5	P70	T6	W10	599
I/O	5	P71	P7	AB10	602
GND	-	P72	GND*	GND*	-
V <sub>CCO</sub>	5	-	V <sub>CCO</sub> Bank 5*	V <sub>CCO</sub> Bank 5*	-
I/O, V <sub>REF</sub>	5	P73	P8	Y10	605
I/O	5	P74	R7	V11	608
I/O	5	-	-	AA10	614
I/O	5	-	T7	W11	617
I/O	5	P75	T8	AB11	620
I/O	5	-	-	U11	623
V <sub>CCINT</sub>	-	P76	V <sub>CCINT</sub> *	V <sub>CCINT</sub> *	-
I, GCK1	5	P77	R8	Y11	635
V <sub>CCO</sub>	5	P78	V <sub>CCO</sub> Bank 5*	V <sub>CCO</sub> Bank 5*	-
V <sub>CCO</sub>	4	P78	V <sub>CCO</sub> Bank 4*	V <sub>CCO</sub> Bank 4*	-
GND	-	P79	GND*	GND*	-



## XC2S200 Device Pinouts (Continued)

XC2S200 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
I, GCK0	4	P80	N8	W12	636
I/O	4	P81	N9	U12	640
I/O	4	-	-	V12	646
I/O	4	P82	R9	Y12	649
I/O	4	-	N10	AA12	652
I/O	4	-	-	W13	655
I/O	4	P83	T9	AB13	661
I/O, V <sub>REF</sub>	4	P84	P9	AA13	664
V <sub>CCO</sub>	4	-	V <sub>CCO</sub> Bank 4*	V <sub>CCO</sub> Bank 4*	-
GND	-	P85	GND*	GND*	-
I/O	4	P86	M10	Y13	667
I/O	4	P87	R10	V13	670
I/O	4	-	-	AB14	673
I/O	4	-	-	W14	676
I/O	4	P88	P10	AA14	679
GND	-	-	GND*	GND*	-
I/O	4	-	-	V14	682
I/O	4	-	-	Y14	685
I/O	4	-	-	W15	688
I/O	4	P89	T10	AB15	691
I/O	4	P90	R11	AA15	694
V <sub>CCINT</sub>	-	P91	V <sub>CCINT</sub> *	V <sub>CCINT</sub> *	-
V <sub>CCO</sub>	4	P92	V <sub>CCO</sub> Bank 4*	V <sub>CCO</sub> Bank 4*	-
GND	-	P93	GND*	GND*	-
I/O	4	P94	M11	Y15	697
I/O, V <sub>REF</sub>	4	P95	T11	AB16	700
I/O	4	-	-	AB17	706
I/O	4	P96	N11	V15	709
GND	-	-	GND*	GND*	-
I/O	4	-	R12	Y16	712
I/O	4	-	-	AA17	715
I/O	4	-	-	W16	718
I/O	4	P97	P11	AB18	721
I/O, V <sub>REF</sub>	4	P98	T12	AB19	724
V <sub>CCO</sub>	4	-	V <sub>CCO</sub> Bank 4*	V <sub>CCO</sub> Bank 4*	-
GND	-	-	GND*	GND*	-
I/O	4	P99	T13	Y17	727
I/O	4	-	N12	V16	730
I/O	4	-	-	AA18	733

## XC2S200 Device Pinouts (Continued)

XC2S200 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
I/O	4	-	-	W17	739
I/O, V <sub>REF</sub>	4	P100	R13	AB20	742
GND	-	-	GND*	GND*	-
I/O	4	-	P12	AA19	745
I/O	4	-	-	V17	748
I/O	4	-	-	Y18	751
I/O	4	P101	P13	AA20	757
I/O	4	P102	T14	W18	760
GND	-	P103	GND*	GND*	-
DONE	3	P104	R14	Y19	763
V <sub>CCO</sub>	4	P105	V <sub>CCO</sub> Bank 4*	V <sub>CCO</sub> Bank 4*	-
V <sub>CCO</sub>	3	P105	V <sub>CCO</sub> Bank 3*	V <sub>CCO</sub> Bank 3*	-
PROGRAM	-	P106	P15	W20	766
I/O (INIT)	3	P107	N15	V19	767
I/O (D7)	3	P108	N14	Y21	770
I/O	3	-	-	V20	776
I/O	3	-	-	AA22	779
I/O	3	-	T15	W21	782
GND	-	-	GND*	GND*	-
I/O, V <sub>REF</sub>	3	P109	M13	U20	785
I/O	3	-	-	U19	788
I/O	3	-	-	V21	794
GND	-	-	GND*	GND*	-
I/O	3	-	R16	T18	797
I/O	3	P110	M14	W22	800
GND	-	-	GND*	GND*	-
V <sub>CCO</sub>	3	-	V <sub>CCO</sub> Bank 3*	V <sub>CCO</sub> Bank 3*	-
I/O, V <sub>REF</sub>	3	P111	L14	U21	803
I/O	3	P112	M15	T20	806
I/O	3	-	-	T19	809
I/O	3	-	-	V22	812
I/O	3	-	L12	T21	815
GND	-	-	GND*	GND*	-
I/O	3	P113	P16	R18	818
I/O	3	-	-	U22	821
I/O, V <sub>REF</sub>	3	P114	L13	R19	827
I/O (D6)	3	P115	N16	T22	830
GND	-	P116	GND*	GND*	-